

In Situ Fabrication Technologies

Technical Interchange Meeting

University of California - Berkeley • May 16-18



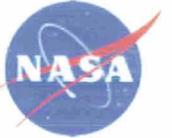
ISFR-Fabrication Technologies: Introduction

Goals:

Purpose of visit

- Introduce the In Situ Fabrication and Repair (ISFR) Element, specifically the Electronics Fabricator
- Understand your strengths/capabilities
- Outline high-level strategies for potential collaboration

OPTEO



ISFR-Fabrication Technologies: Description

OPTRONICS

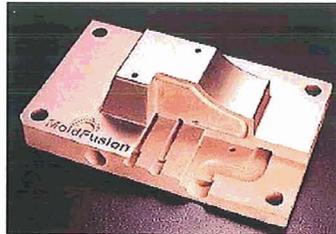
Fabrication Technologies is a sub element of the In Situ Fabrication & Repair (ISFR) element

- Supports long duration spaceflights by providing contingency manufacturing capabilities for the moon and Mars exploration missions
- Fabrication Technologies provide fabrication of tools, parts and structural components using in situ, recycled and provisioned resources (via a Multi-Material Fabricator)
- Materials investigated will include metals, plastics, composite and ceramics, through use of additive and/or subtractive techniques
- Trade Studies completed in FY05 identify leading technologies for further development in FY06
- Electronics Fabricator is a stand alone effort with some synergy with the Multi-Material Fabricator
- Dr. Terry D. Rolin has been assigned project lead on the Electronics Fabricator effort to initiate early activities in order to aggressively approach technology development activities in FY06



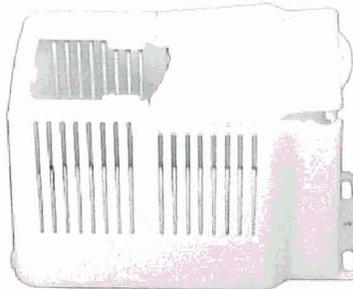
In Situ Fabrication and Repair Fabrication Technologies: Overview

Metals



- Replacement Parts
- Unforeseen Tools
- Conformal Repair Patches
- Habitat Fittings

Plastics

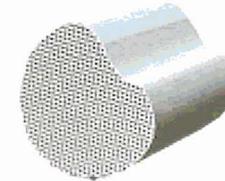


Ceramics



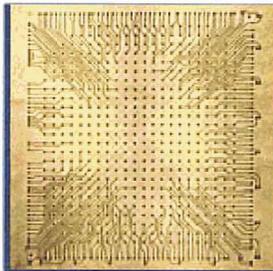
- Alumina
- Zirconia
- Silica
- Silicon nitride
- Misc. oxides

Biological

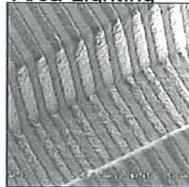


- Biodegradable bone supports
- Tissue, skin, dental & organ applications

Electronics



- PC Boards
- Discrete Components
- Crew Displays
- Area Lighting



ISFR-Fabrication

- In-Transit Tools & Parts
- On-Surface Tools & Parts

- Trade Study of Processes: Additive, Subtractive, Hybrid

- Three Dimensional Printing
- Computer Numerical Control
- Direct Metal Process
- Electron Beam Freeform Fabrication
- Electron Beam Melting: Distributed by Vendor "Arcam"
- Fused Deposition Modeling
- Kinetic Metallization
- Laser Engineered Net Shaping
- Laminated Object Manufacturing
- Precision Metal Deposition
- Stereolithography
- Selective Inhibition of Sintering
- Selective Laser Melting
- Selective Laser Sintering
- Ultrasonic Object Consolidation

Manufacturing Processes

Products



6.) First 8 Weeks



7.) 8 Weeks Growth

OPTICS



Fabrication Technologies – Scope

Metals

- Aluminum Alloys
- Titanium Alloys
- Stainless Steels
- Super alloys
- Others TBD

Stainless/Bronze Gear



Aluminum Gear



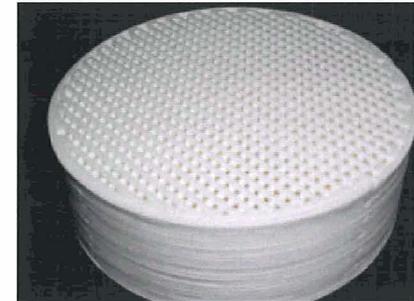
ECLSS Vapor Compression Distillation System

ISFR – Fabrication Technologies

- In-Transit & Surface Products
- Replacement Parts
- Unforeseen Tools
- Conformal Repair Patches
- Habitat Fittings
- ECLSS Parts
- Exercise Equipment
- Elastomer Seals

Ceramics

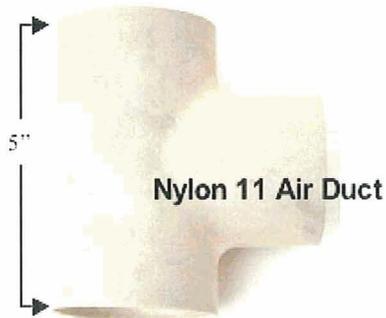
- Alumina
- Zirconia
- Silica
- Silicon nitride
- Others TBD



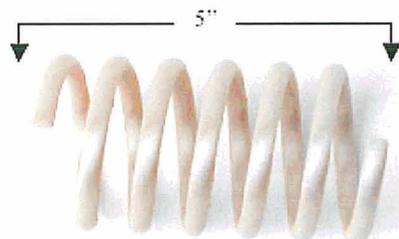
Alumina Filter

Plastics

- ABS Plastics
- Poly Carbonate
- Polyphenylsulfone
- Others TBD



Nylon 11 Air Duct



Polyphenylsulfone Spring

Composites

- Fiber/Resins
- Amalgams
- Infiltrated Structures
- Others TBD



Alumina/Molybdenum Cermet Traces on Alumina Rod
Integral Heater Element

OPTICS



Core Capability: Fabrication of Multi-Material Parts Up To 18" x 18" x 18" in Hypo-G & Micro-G
Sub-Capabilities: Metal, Plastic, Ceramic & Composite Parts; Integral NDE for QA & Process Control

Capability Description

- Manufacturing system internal to controlled cabin environment to produce functional parts to net shape with sufficient tolerances, strength and integrity to meet application specific needs such as CEV ECLS components, robotic arm or rover components, EVA suit items, unforeseen tools, conformal repair patches, and habitat fittings among others.
- Except for start-up and shut-down, fabrication will be automatic without crew intervention under nominal scenarios. Off-nominal scenarios may require crew and/or Earth control intervention.
- Parts build processing files may be loaded from in-situ library or from Earth.
- Integral NDE functions will provide QA & process control as well as ability to scan in existing part surface geometry for modifications or repair.
- System will have ability to fabricate using both provisioned feedstock materials and feedstock refined from in situ regolith.
- Furnace station will provide post build heat treatment, sintering and porous part infiltration functions.

Assumptions

- Power will be available up to 48 hours continuously from carrier or habitat to perform complete build cycle.
- Crew will be available to exchange feedstock, transfer parts to heat treatment furnace, perform parts cleaning, and remove parts.
- Crew will be available to provide support for off-nominal operation scenarios.

Spiral Applicability

Spiral 3, 4, 5: System will be plug and play once landed using power from carrier vehicle, cargo transfer module or habitat module. Once powered up and feedstock is loaded, system will be ready to fabricate hardware. Spiral 5 system will add Mars regolith products to materials processing set compared to Spiral 3 Lunar system.

Metals



Electronics



- Replacement Parts
- Unforeseen Tools
- Conformal Patches
- Habitat Fittings
- ECLS Parts
- Robotic Rover Components
- Thermal Management Parts
- Radiation Shielding Panels

Plastics



Ceramics



Composites



Product Performance Characteristics

Product Materials	
Metal	Ti6Al4V, Al2219, Al6061, SS304, SS316, W
Polymer	Poly carbonate, PPS, Polyimide
Ceramic	Oxides, Nitrides (e.g. Alumina)
Composite	Resins, Cermets, FGMs
Exclusions	Materials w/M.P. > 2,500 C may require bulk feedstock machining
Product Environ. (IVA, EVA)	Application Specific
Product Strength	≥ 70% of Wrought Values
Product Geometry	3D Contours, Internal Channels, Overhangs, Undercuts, etc.
Product Tolerances (inches)	L ≤ 6: ±0.005; L > 6: ± 0.005 in/in
Product Surface Finish	≥ 32 μ-in RMS
Product Life; Restrictions	Application Specific; None
Product Availability Time	Less than 48 Hours

Capability Infrastructure Characteristics

Operational Gravity	Hypo-g & Micro-g
Operational Environment	Cabin IVA; T=10-35 C, P=10-15psia
Shelf Life; Operating Life	5 years; 5 years
Operating Mode	Crew Tended
System Reliability	≥ 95% Uptime

OPERATIONAL CAPABILITY



In-Situ Fabrication of Electronics: Phase I

Instrument and Payload Systems Department— Dr. Terry D. Rolin, Project Lead

Objectives:

- Understand current state of the art techniques and technology levels of 3-D electronic design and prototyping to accomplish art to part for electronic components and assemblies
- Understand the feasibility of producing electronic boards with both internal components (embeddeds) and/or piece parts (resistors, capacitors, diodes, etc.)
- Understand materials available on lunar surface for feedstock (iron, silicon, aluminum, etc.) as well as novel material concepts (conductive inks and polymers)
- Layout requirements for approach to Phase II

Approach:

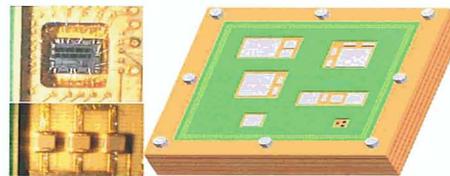
- Capture current knowledge base by research, conference participation, and travel as necessary
- Current understanding and test data indicate that passives are more prevalent and have higher fail rates therefore we must pursue fabricating them first
- Perform initial evaluation testing and fabrication of passives using current onsite technology
- Establish teaming relationships that will aid in faster Spiral development

Challenges:

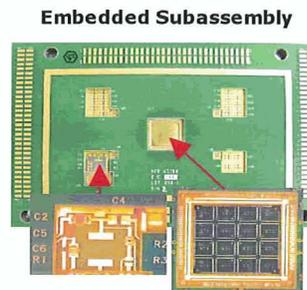
- Transforming terrestrial processes to microgravity processes
- Power
- Fabrication of piece parts that are multi-material and assemblies that are multi-material and multi-component

Benefits:

- Lower mass and volume for terrestrial launch
- Repair or replacement of failed parts onsite and on time
- Potential for future injection of novel fabrication techniques into commercial sector



MSFC Model of Stacked Substrate Embedded Component (solderless box-less cube)
400-600% size reduction



Why Instrument and Payload Systems Department?

- Rapid prototyping technologies are present at the center to serve as a first phase test bed
- Our packaging team alone has over 150 years of combined experience working electronic fabrication issues and problems both in-house and at contractor facilities
- We have authored or co-authored numerous MSFC, NASA and industry process standards for fabrication of electronics
- Extensive experience and capabilities in assembly, thermal test and failure analysis

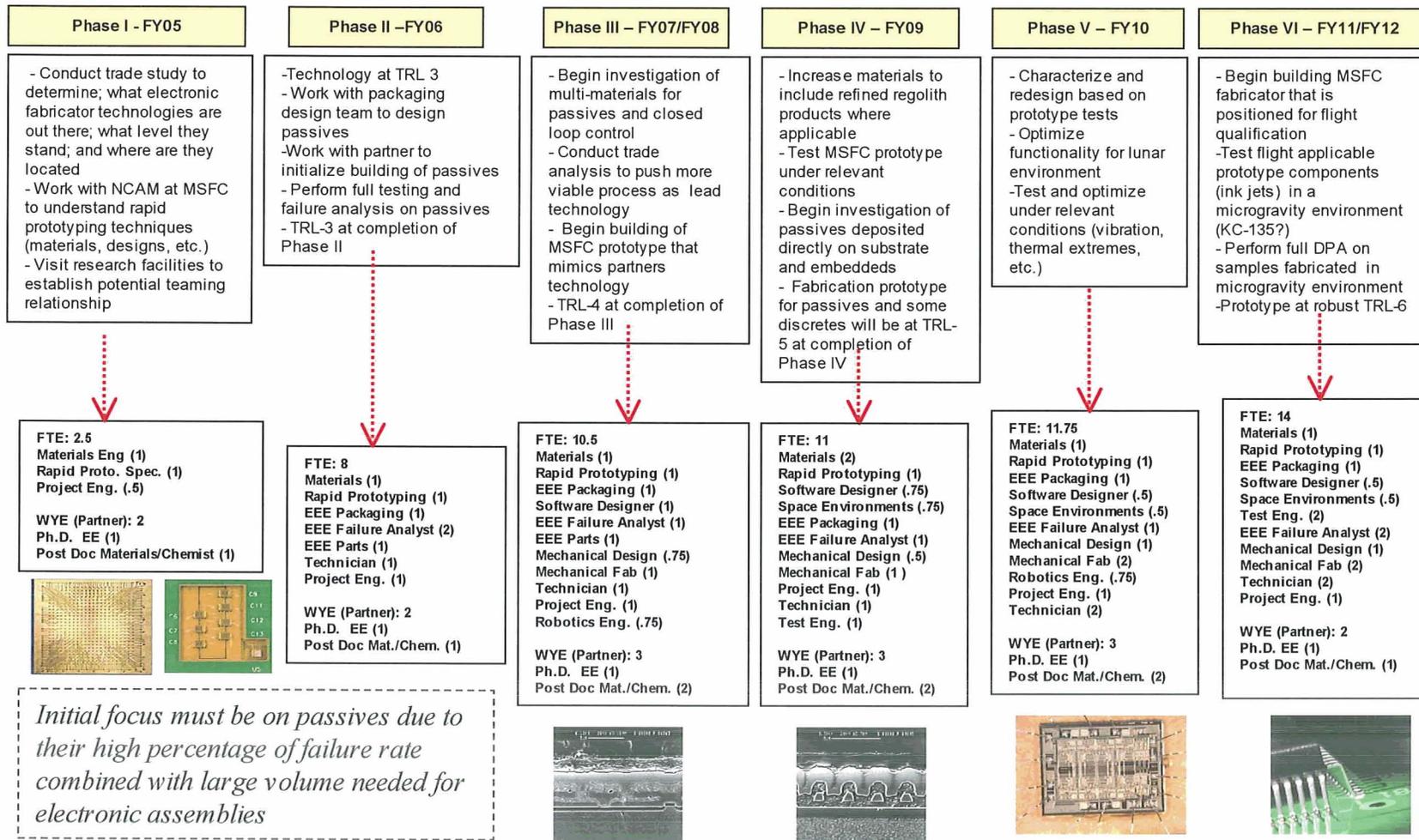
OPTESS



Electronic Fabricator Capability Evolution Roadmap

Current State of the Art: Rapid prototyping technologies are advancing but....

- Currently not possible to build complex circuits on substrates through automated process
- Currently no standards for design, test, and FA of the piece parts
- Currently no push to move capability from terrestrial to microgravity environment



OPTICS



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DATA FROM A RECENT PAPER BY LLOYD CONDRA OF
BOEING AEROSPACE PHANTOM WORKS

- **PROJECTED PIECE PART REQUIREMENTS 2003-2010**

- **MICROPROCESSORS** **444,000**
- **MEMORIES** **668,000**
- **OTHER ICs** **11,200,000**
- **DISCRETES** **20,000,000**
- **PASSIVES** **114,000,000**
- **MISCELLANEOUS** **84,000**

Clearly the bulk of electronics failures will come from passives

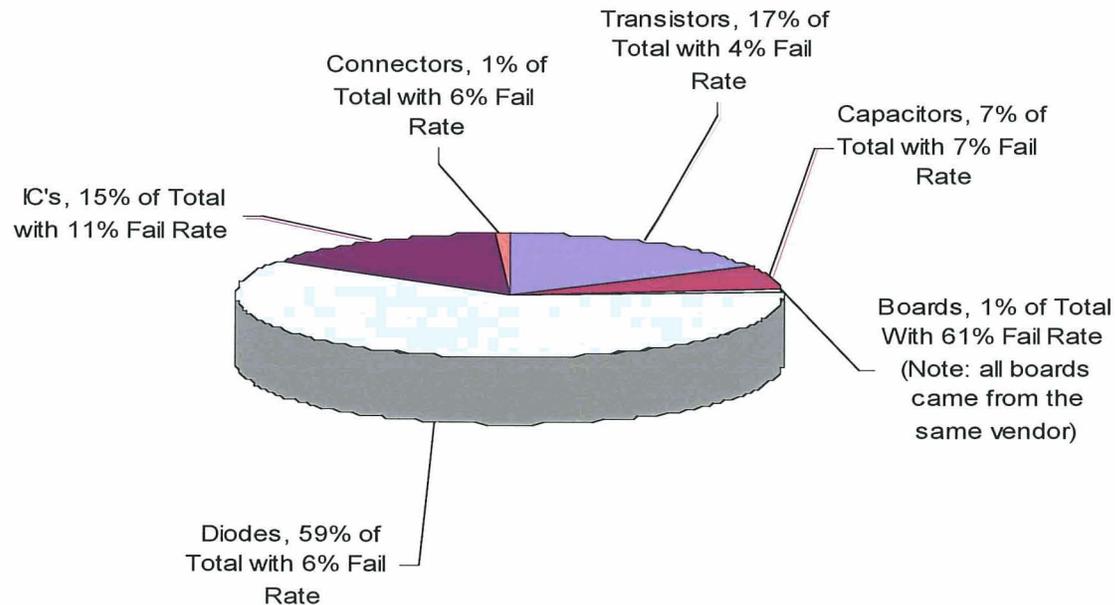
OP&S



MSFC Screening and FA Results

MSFC Internal Failures (screening, DPA, and field failures) (2003-2005)

Total of 3283 Components with 230 Failures (7%)
ECLSS represents >95% of Jobs



Typical Failure Mechanisms

Note: Most failures came from manufacturer, not during use in the field

Transistors: ESD, EOS, thermal runaway, failure to meet spec

Capacitors: Dielectric leakage, failure to meet specs

Boards: Workmanship, failure to meet specs

Diodes: ESD, EOS, failure to meet specs

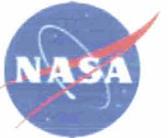
IC's: ESD, EOS, failure to meet specs

Connectors: Workmanship, failure to meet specs

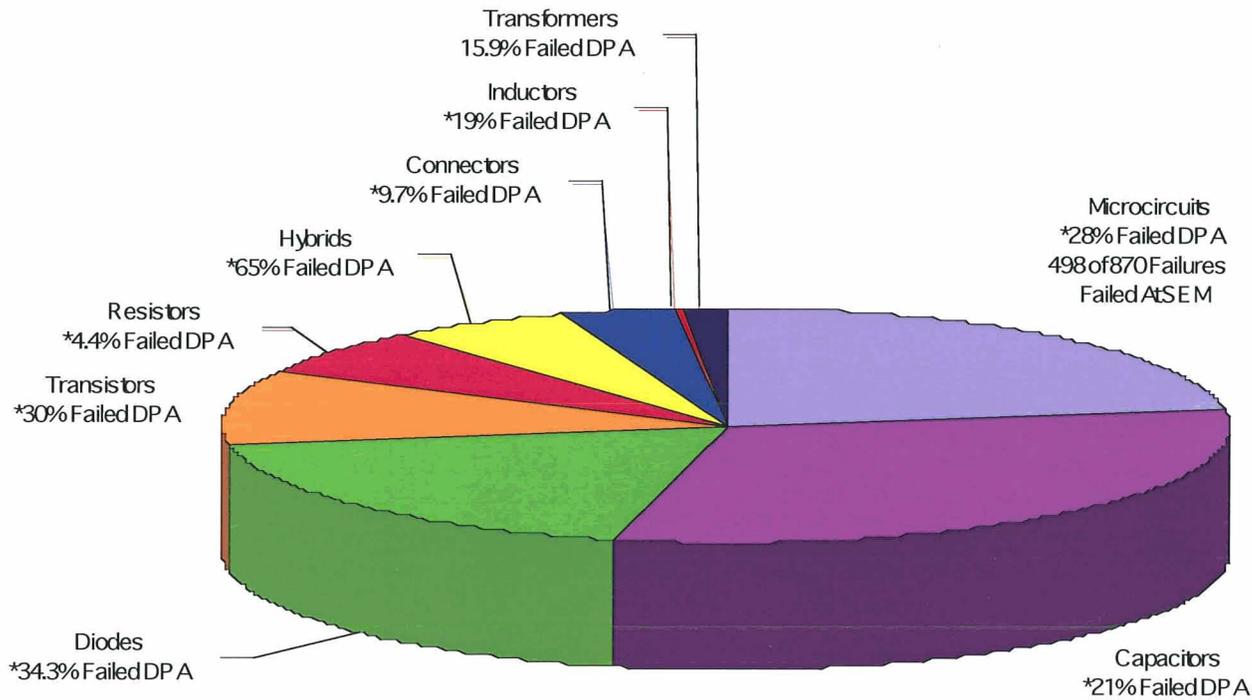
OPERATIONS



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**DPA (Destructive Physical Analysis) Results Within Part Type Distribution
For 1989-90, 97-99 (11,442 DPA's Performed)
Overall DPA Failure Rate Was 25.4%**



*Denotes DPA Failure Rate per DPA's performed

Diodes and capacitors represent approximately 50% of the 11,442 DPA's performed

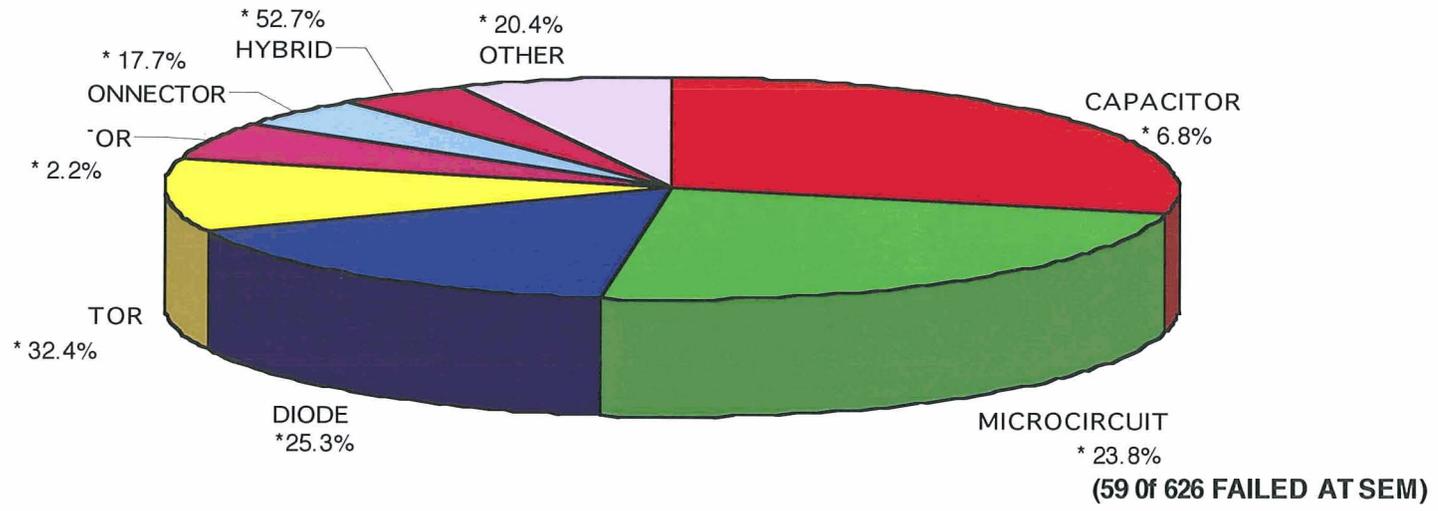
Note: Passives represent the largest percentage of total failures

OPTICS



OPTICS

DESTRUCTIVE PHYSICAL ANALYSIS (DPA) RESULTS WITHIN PART TYPE DISTRIBUTIONS FOR 01/2001 – 01/2002 TOTAL DPA FAILURE RATE WAS 19.7% (2633 DPA'S PERFORMED)

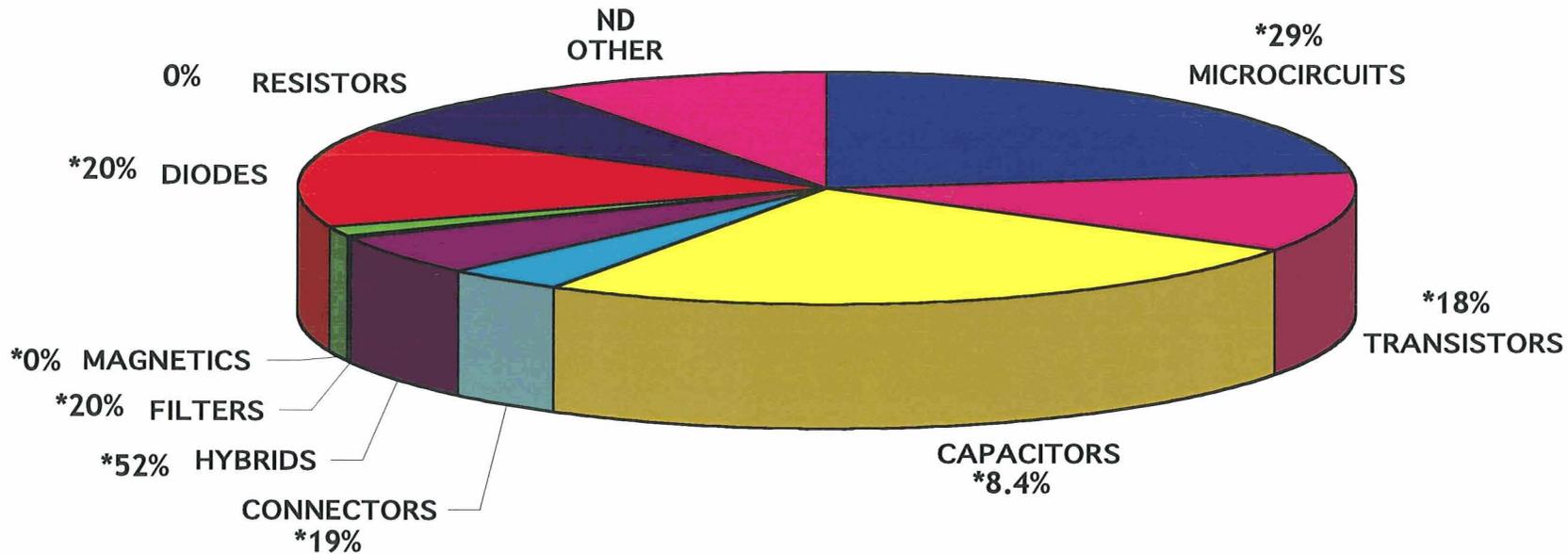


*Denotes DPA Failure Rate

CAPACITOR	MICROCIRCUIT	DIODE	TRANSISTOR
RESISTOR	CONNECTOR	HYBRID	OTHER



2003 DPA RESULTS



*** DPA FAILURE RATE WITHIN PART TYPE DISTRIBUTIONS FOR YEAR 2003 (2240 DPAs PERFORMED). 18% OVERALL FAILURE RATE OBSERVED.**

0 1 2 3 4 5 6 7 8 9 10 11 12 13 14 15 16 17 18 19 20 21 22 23 24 25 26 27 28 29 30 31 32 33 34 35 36 37 38 39 40 41 42 43 44 45 46 47 48 49 50 51 52 53 54 55 56 57 58 59 60 61 62 63 64 65 66 67 68 69 70 71 72 73 74 75 76 77 78 79 80 81 82 83 84 85 86 87 88 89 90 91 92 93 94 95 96 97 98 99 100



ISFR-Fabrication Technologies Summary

- **Based on recent failure analyses, NASA recognizes the need to use novel/cutting edge technologies for electronics fabrication**
- **Electronic Fabricator is a complement of the Fabrication Technologies Program Operating Plan FY06 baseline budget submit**
- **Additional “out year” funding is contingent on relevancy to program objectives, with a development process current with the technology development spirals phased to support the fundamental spirals defined for Human Exploration of Space Program**
- **What we desire is:**
 - Expertise in developing the materials/feedstock for electronic fabricator concept/application
 - Initiate hardware development activities, to include breadboard fabrication and integration

OPERATIONS



ISFR-Fabrication Technologies: Contacts

OPPO

- Monica Hammond/SY10 Project Manager
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- Richard Hagood/SP33 Systems Engineer
544-4922
- Dr. Terry D. Rolin/EI42 Electronics Fabrication Lead
544-5579

For more information... <http://est.msfc.nasa.gov/ISFR/fab.html>